Instrument Name: **ToF-SIMS**  
Manufacturer: *Physical Electronics Inc (PHI)*  
Model: **TRIFT III**  
Manufacturer Year: **2000**

- Ga ion primary beam source  
- Ar/O₂ gas sputter gun  
- High mass resolution mass spectrum  
- High lateral resolution elemental mapping  
- High resolution depth profiling  
- Excellent working condition

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